Search Notes



Application/Control No.

Applicant(s)/Patent under Reexamination

JOHNSON ET AL.
Art Unit

09/848,723 Examiner

Djenane M. Bayard

2141

SEARCHED				
Class	Subclass	Date	Examiner	
709	224	2/13/2006	DB	
709	203	2/13/2006	DB	
709	218	2/13/2006	DB	
709	232	2/13/06	DB	
707	204	2/13/2006	DB	
707	205	2/13/2006	DB	

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
709	224/232	2/13/2006	DB		
709	203/218	2/13/2006	DB		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
East	2/13/2006	DB .		
IEEE, google scholar	2/13/2006	DB		